

# Virtual DoE → selection of molding compound based on FEM simulation

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Motivation:

- 1) Complexity of the electronic control units is increasing
- 2) New materials in consideration
- 3) Shorten design cycle time

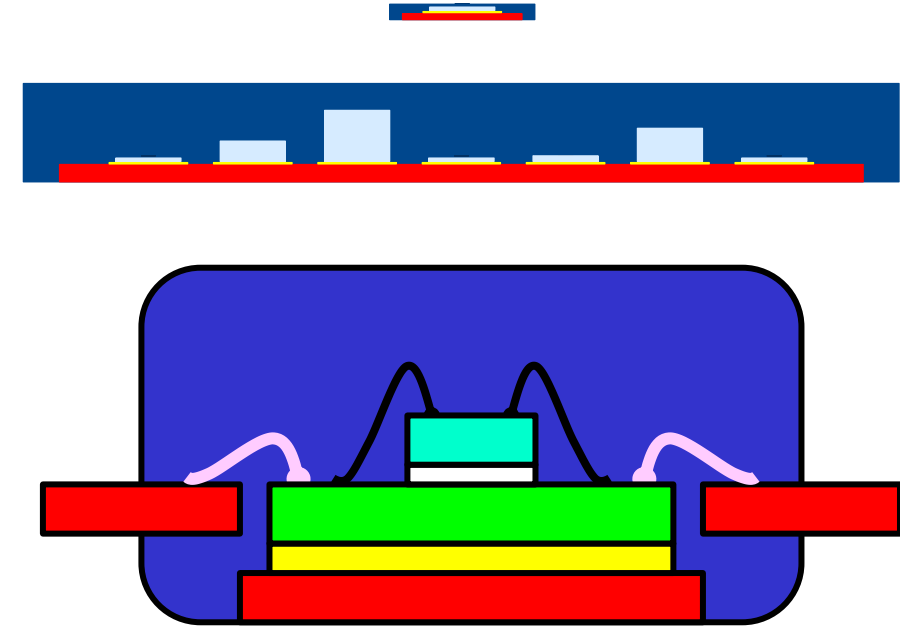
## Agenda

- Introduction
- Simulation driven design
- Virtual Design of Experiment
- Benefits of VDoE
- Validation of VDoE
- Summary



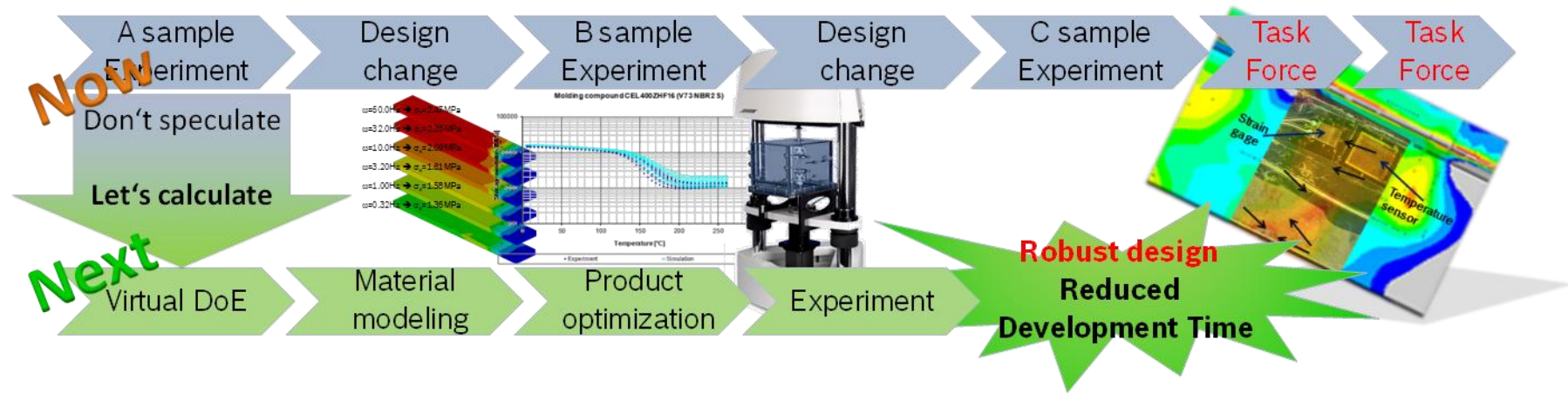
## Introduction

- New generation of vehicles → the amount of ECUs used is increasing.
- New solution must be cost effective.
- Multi-functionality within one robust package appears to be an interesting solution.
- Relative large size of the module leads to high stress at the integrated circuitry.



# Concept of the Virtual Design of Experiment for Development of the Molded Electronic Control Units

## Simulation driven design

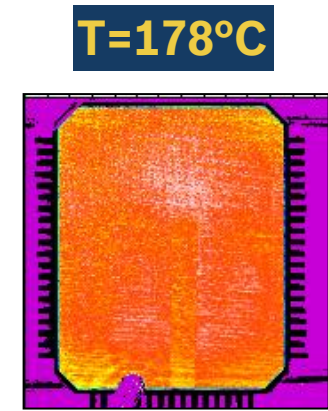
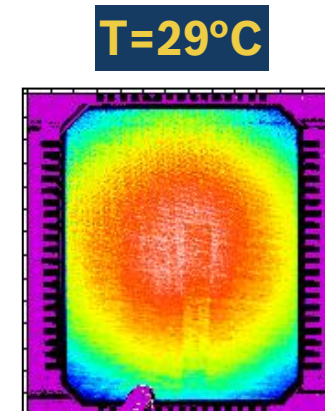
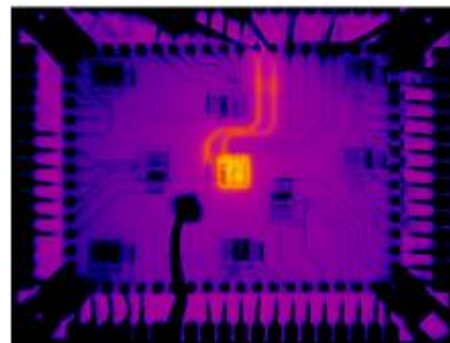
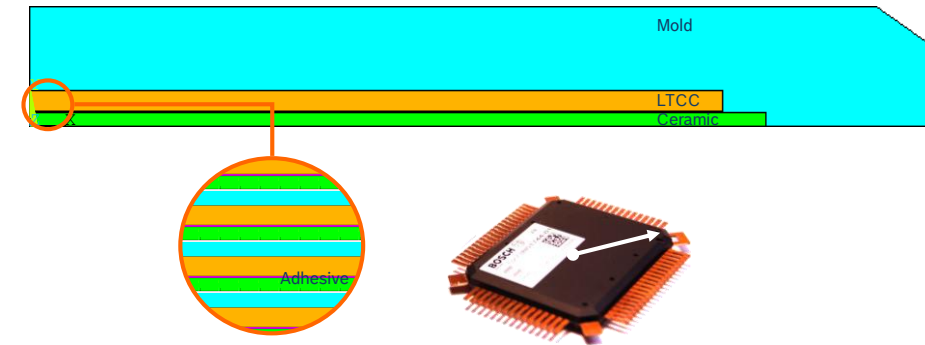


Virtual DoE has a great potential here.

# Concept of the Virtual Design of Experiment for Development of the Molded Electronic Control Units

## Molded electronic control unit

- Entire integrated circuitry overmolded.
- Based on LTCC technology.
- Challenges:
  - Thermal – heat generation
  - Thermo-mechanical – temperature dependent deformation

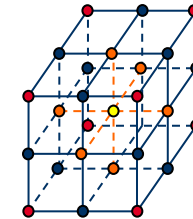
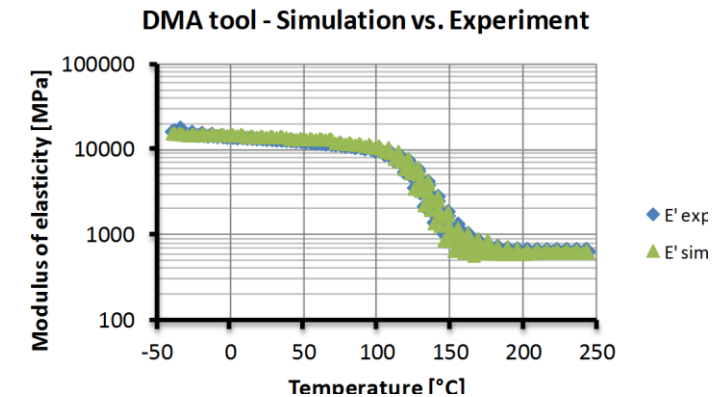
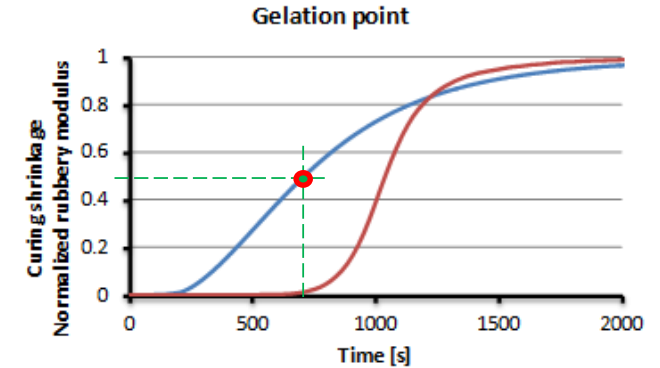


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## Design of experiment

### Molding compound – composite material used for encapsulating of semiconductor devices and electronic control units



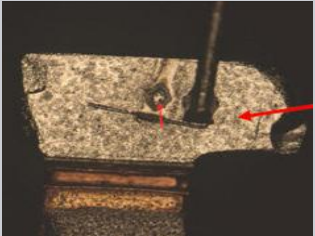
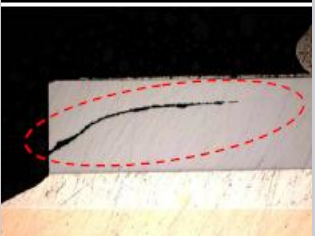
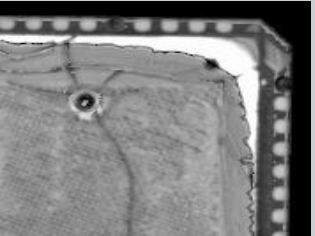
- Properties changes during the manufacturing process.
- Time/temperature dependent.
- Parameters of molding compound (DoE design):
  - CTE1 – 6 ... 20 [ppm/K]
  - CTE2 – 25 ... 50 [ppm/K]
  - Tg – 100 ... 200 [°C]
  - Shrink – 0.0 ... 0.4 [%]
  - E – 12500 ... 30000 [MPa]



Covers wide range of available molding compounds

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## Typical failure mode in semiconductor

Crack in molding compound	Delamination	Wire bond lift off	Crack in silicon	Crack in substrate
				

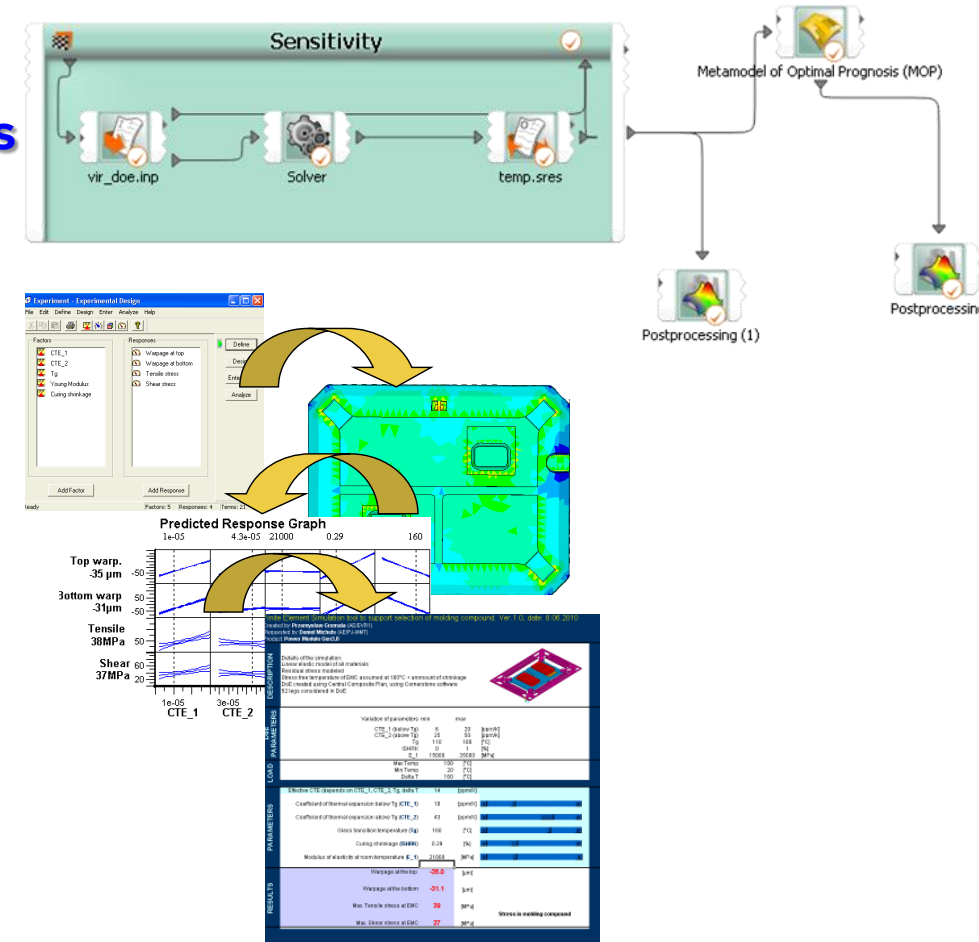
**Can the prognosis be made for all possible failure modes?**

# Concept of the Virtual Design of Experiment for Development of the Molded Electronic Control Units

## Optimization schemes

**Understand the effect of the molding compound properties on the stress in molded control unit.**

- ➔ Parameter identification – OptiSLang:
  - Sensitivity analysis.
  - Metamodel of optimal prognosis (MOP).
- ➔ Design of experiment – Cornerstone.



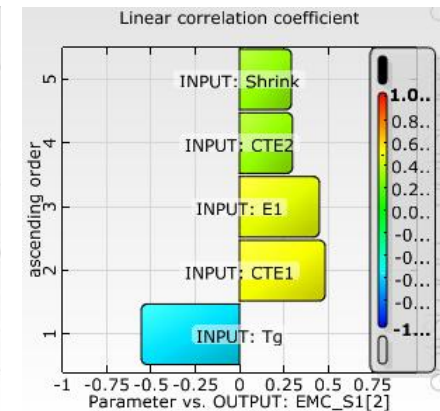
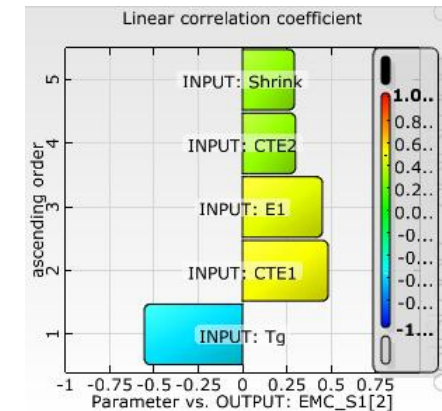
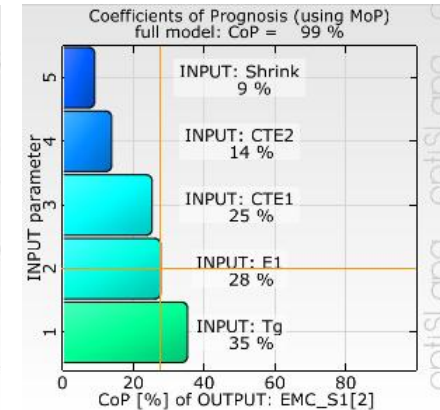
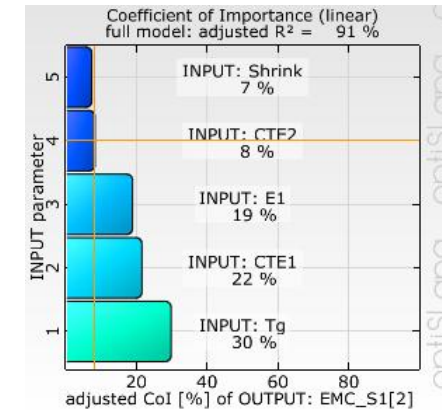
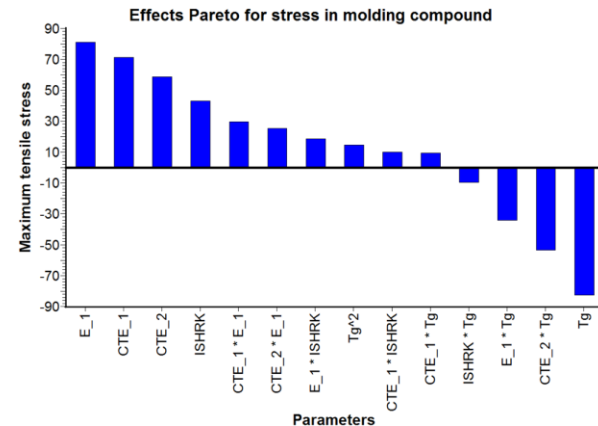


# Concept of the Virtual Design of Experiment for Development of the Molded Electronic Control Units

## Stress in the mold

### Reduce the risk of the molding compound fracture.

- What influence the stress
  - Main parameter is  $T_g$ .
  - CTE and E are the second most important factor.
- **Recommendation: high  $T_g$ , low CTE and low E.**

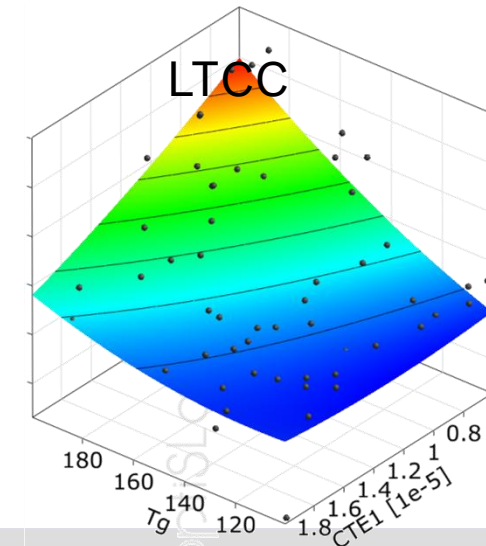
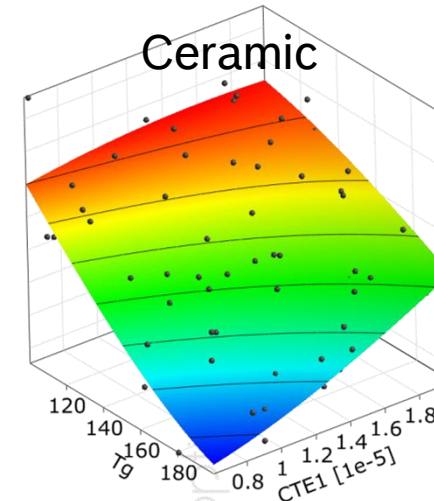
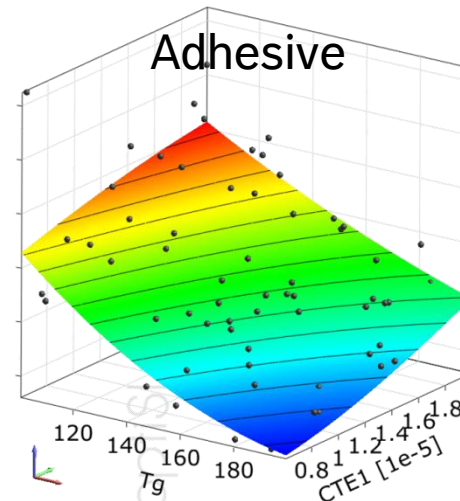


# Concept of the Virtual Design of Experiment for Development of the Molded Electronic Control Units

## Stress in adhesive, ceramic, LTCC

**Reduce the stress in the all other materials.**

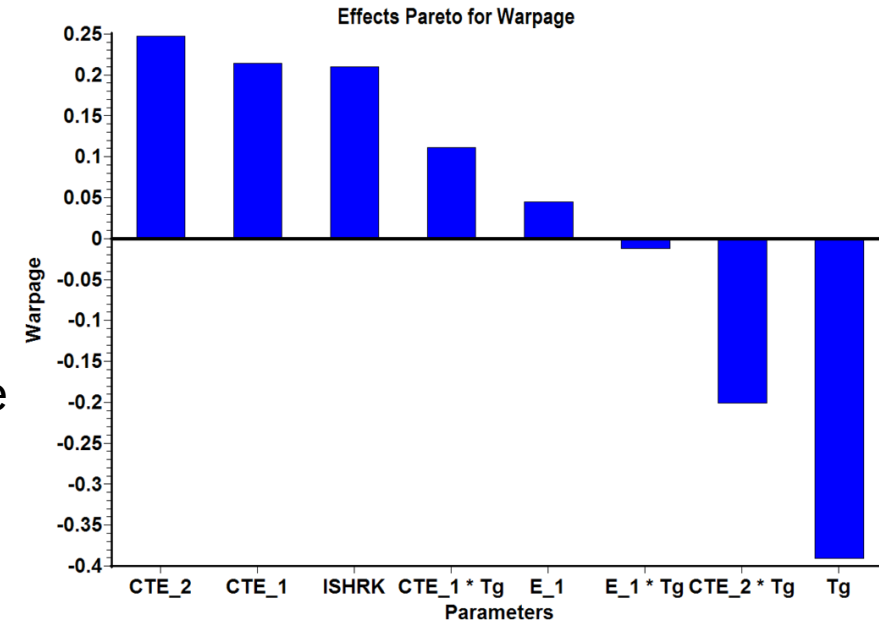
- What influence the stress:
  - Glass transition temperature is the most important parameter.
  - CTE plays second most important role.
  - Modulus of elasticity of molding compound doesn't play significant role.
- **Recommendation: Higher Tg and lower CTE.**



## Warpage

**Deformation over the temperature should be low.**

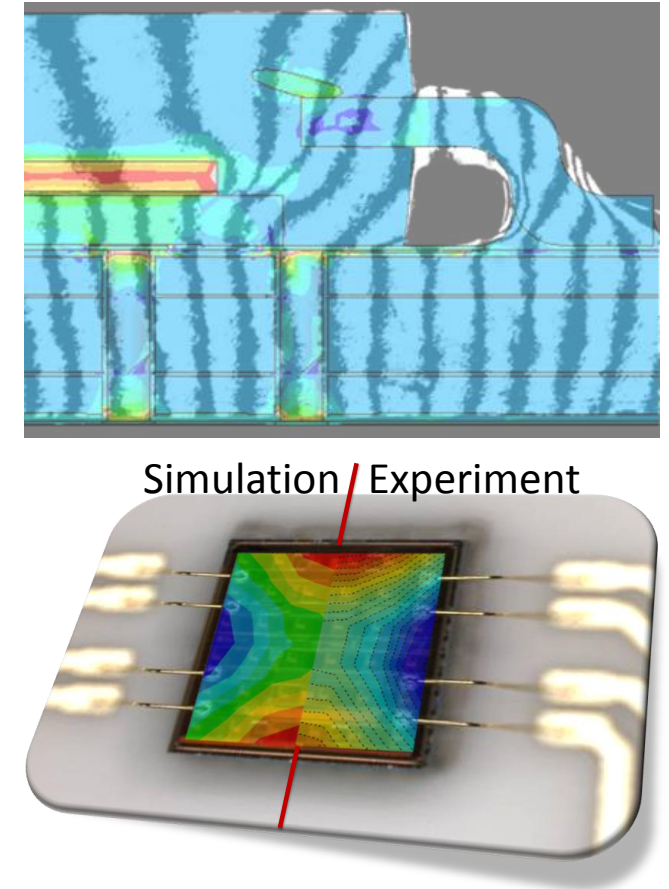
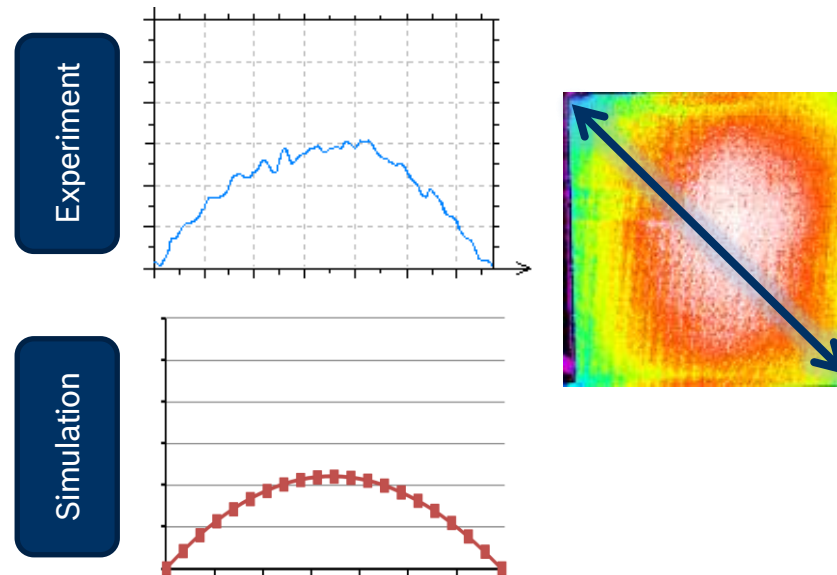
- What influence the warpage
  - Main parameter is  $T_g$ .
  - CTE and curing shrinkage are the second most important factor.
  - Modulus of elasticity doesn't play important role.
- **Recommendation: high  $T_g$ , low CTE and curing shrinkage.**



# Concept of the Virtual Design of Experiment for Development of the Molded Electronic Control Units

## Validation

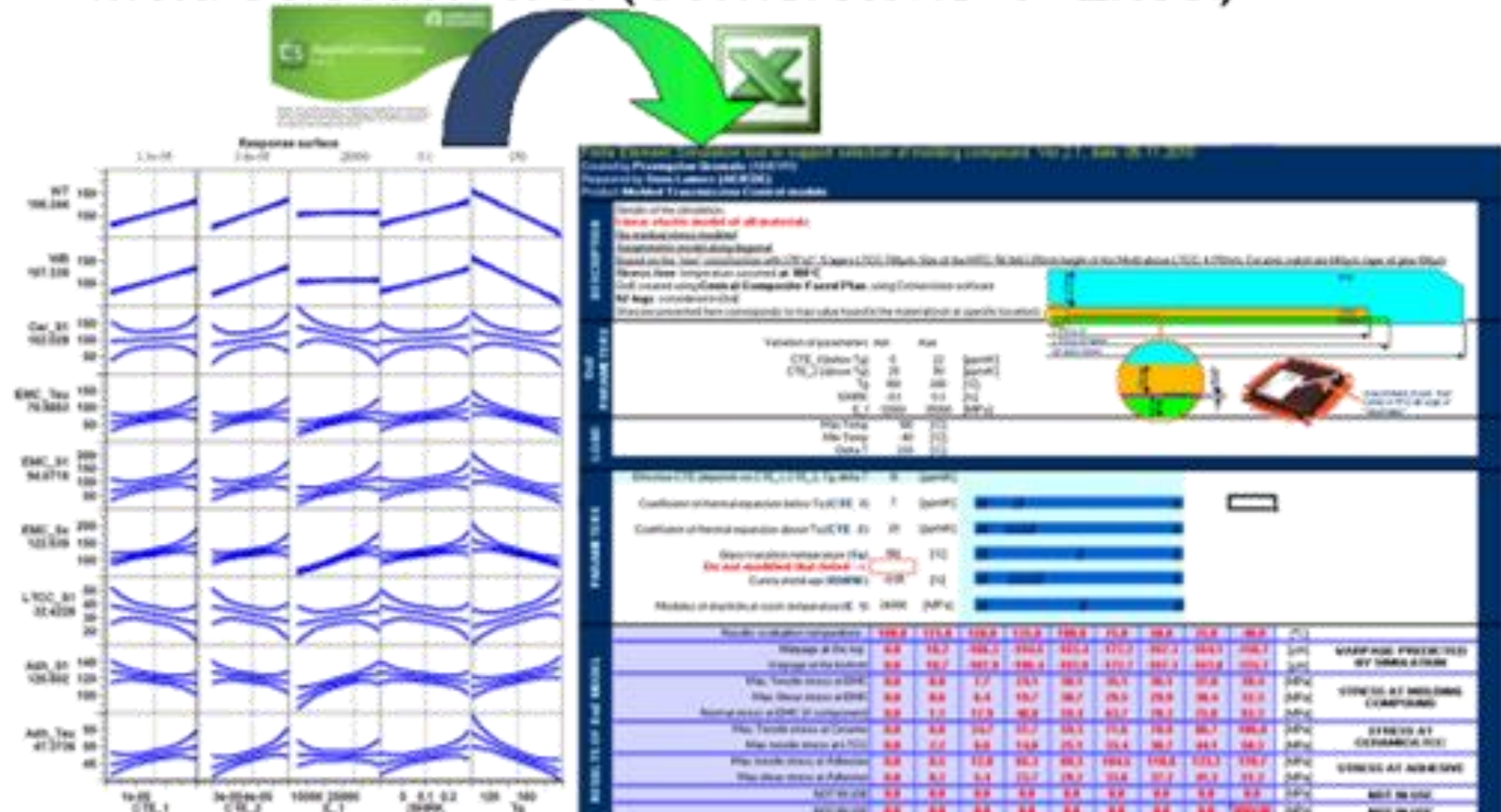
**W. Beveridge: “no one believes an hypothesis except its originator but everyone believes an experiment except the experimenter”.**





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## Mold selection tool (Cornerstone → Excel)



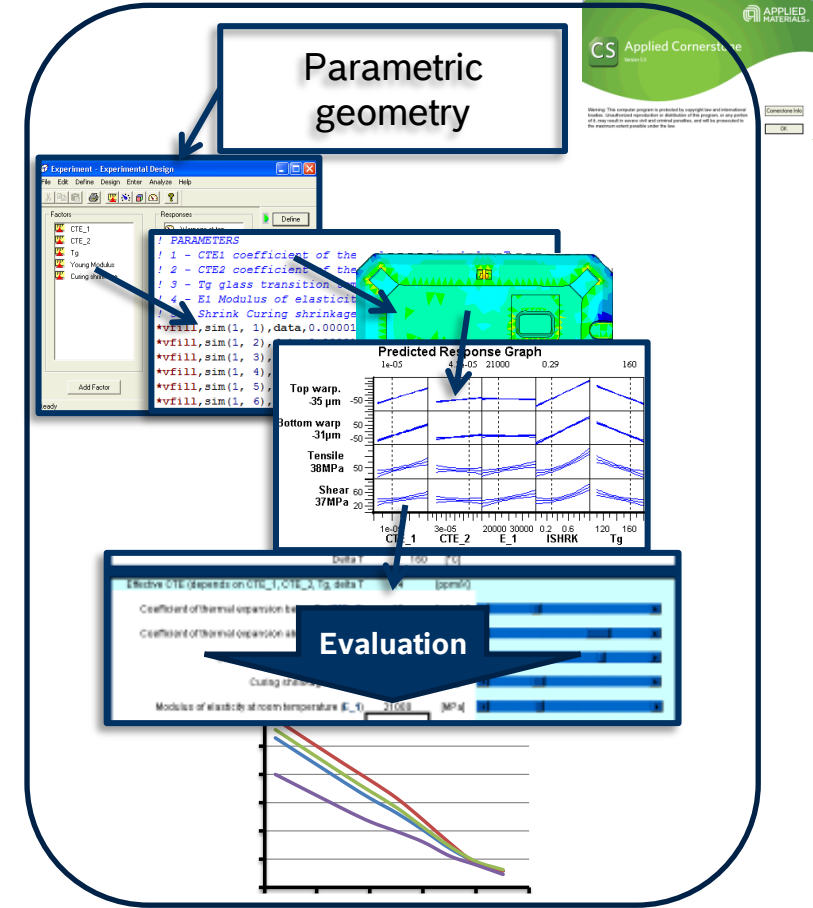
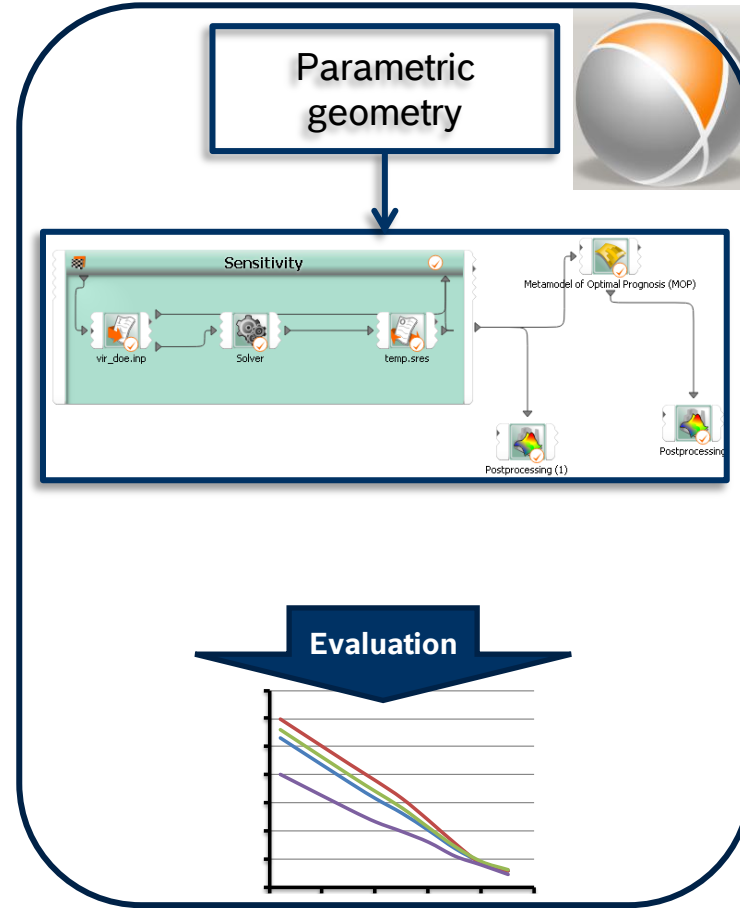
# Concept of the Virtual Design of Experiment for Development of the Molded Electronic Control Units

## FEM vs. OptiSLang vs. Cornerstone

	FEM simulation REFERENCE	OptiSLang COI Quadratic	OptiSLang COP	Cornerstone
Warpage [%]	100	99.9	98.0	101.6
Stress in mold [%]	100	104.1	101.6	96.9
Stress in adhesive [%]	100	101.5	101.0	103.2
Stress in LTCC [%]	100	100.5	99.7	101.0
Stress in ceramic [%]	100	99.8	103.5	96.5

# Concept of the Virtual Design of Experiment for Development of the Molded Electronic Control Units

## Process flow



# Concept of the Virtual Design of Experiment for Development of the Molded Electronic Control Units

## Potentials of Virtual DoE technique

- Virtual DoE technique can significantly accelerate the design process of the electronic control units → lower development costs.
- Selection of the molding compound can be supported by numerical simulation taking into account variation of the material properties of the mold.
- For specific application such as LTCC, PCB or DBC substrate BOM can be defined based on the internal stress distribution and deformation, long time before first samples are manufactured.

**Is it possible to use the results MOP directly in excel?**